

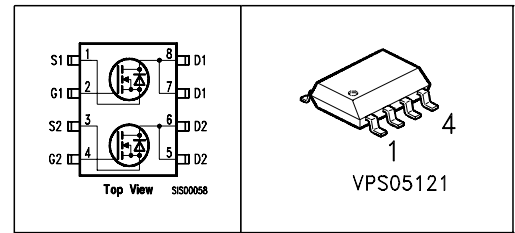
OptiMOS® Small-Signal-Transistor

Feature

- N-Channel
- Enhancement mode
- Logic Level
- Excellent Gate Charge x $R_{DS(on)}$ product (FOM)
- 150°C operating temperature
- Avalanche rated
- dv/dt rated
- Ideal for fast switching applications

Product Summary

| | | |
|--------------|----|----|
| V_{DS} | 30 | V |
| $R_{DS(on)}$ | 20 | mΩ |
| I_D | 8 | A |



| Type | Package | Ordering Code | Marking |
|---------|---------|---------------|---------|
| BSO4804 | SO 8 | Q67042-S4097 | 4804 |

Maximum Ratings, at $T_j = 25^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Value | Unit |
|--|--------------------------|-------------|-------------------|
| Continuous drain current $T_A=25^\circ\text{C}$ $T_A=70^\circ\text{C}$ | I_D | 8 6.4 | A |
| Pulsed drain current $T_A=25^\circ\text{C}$ | $I_{D \text{ puls}}$ | 32 | |
| Avalanche energy, single pulse $I_D=8 \text{ A}$, $V_{DD}=25\text{V}$, $R_{GS}=25\Omega$ | E_{AS} | 90 | mJ |
| Reverse diode dv/dt $I_S=8\text{A}$, $V_{DS}=24\text{V}$, $di/dt=200\text{A}/\mu\text{s}$, $T_{j\text{max}}=150^\circ\text{C}$ | dv/dt | 6 | kV/ μs |
| Gate source voltage | V_{GS} | ± 20 | V |
| Power dissipation $T_A=25^\circ\text{C}$ | P_{tot} | 2 | W |
| Operating and storage temperature | T_j , T_{stg} | -55... +150 | $^\circ\text{C}$ |
| IEC climatic category; DIN IEC 68-1 | | 55/150/56 | |

Thermal Characteristics

| Parameter | Symbol | Values | | | Unit |
|--|------------|--------|------|------|------|
| | | min. | typ. | max. | |
| Characteristics | | | | | |
| Thermal resistance, junction - soldering point | R_{thJS} | - | - | 45 | K/W |
| SMD version, device on PCB: | R_{thJA} | | | | |
| @ min. footprint; t ≤ 10 sec. | | - | - | 110 | |
| @ 6 cm ² cooling area ¹⁾ ; t ≤ 10 sec. | | - | - | 62.5 | |

Electrical Characteristics, at $T_j = 25$ °C, unless otherwise specified

| Parameter | Symbol | Values | | | Unit |
|--|---------------|--------|------------|----------|------------|
| | | min. | typ. | max. | |
| Static Characteristics | | | | | |
| Drain-source breakdown voltage $V_{GS}=0V, I_D=1mA$ | $V_{(BR)DSS}$ | 30 | - | - | V |
| Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D=30\mu A$ | $V_{GS(th)}$ | 1.2 | 1.6 | 2 | |
| Zero gate voltage drain current $V_{DS}=30V, V_{GS}=0V, T_j=25^{\circ}C$ $V_{DS}=30V, V_{GS}=0V, T_j=125^{\circ}C$ | I_{DSS} | - - | 0.01 10 | 1 100 | μA |
| Gate-source leakage current $V_{GS}=20V, V_{DS}=0V$ | I_{GSS} | - | 1 | 100 | |
| Drain-source on-state resistance $V_{GS}=4.5V, I_D=6.7A$ | $R_{DS(on)}$ | - | 23.8 | 28.2 | m Ω |
| Drain-source on-state resistance $V_{GS}=10V, I_D=8A$ | $R_{DS(on)}$ | - | 17.4 | 20 | |

¹Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical without blown air.

Electrical Characteristics, at $T_j = 25\text{ }^{\circ}\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Values | | | Unit |
|------------------------------|--------------|--|--------|------|------|----------|
| | | | min. | typ. | max. | |
| Dynamic Characteristics | | | | | | |
| Transconductance | g_{fs} | $V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}$, $I_D=6.4A$ | 8.5 | 17 | - | S |
| Input capacitance | C_{iss} | $V_{GS}=0V$, $V_{DS}=25V$, $f=1MHz$ | - | 700 | 870 | pF |
| Output capacitance | C_{oss} | | - | 300 | 370 | |
| Reverse transfer capacitance | C_{rss} | | - | 74 | 110 | |
| Gate resistance | R_G | | - | 1.1 | - | Ω |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD}=15V$, $V_{GS}=4.5V$, $I_D=6.7A$, $R_G=9.1\Omega$ | - | 9.1 | 14 | ns |
| Rise time | t_r | | - | 27 | 40 | |
| Turn-off delay time | $t_{d(off)}$ | | - | 18 | 27 | |
| Fall time | t_f | | - | 24 | 36 | |

Gate Charge Characteristics

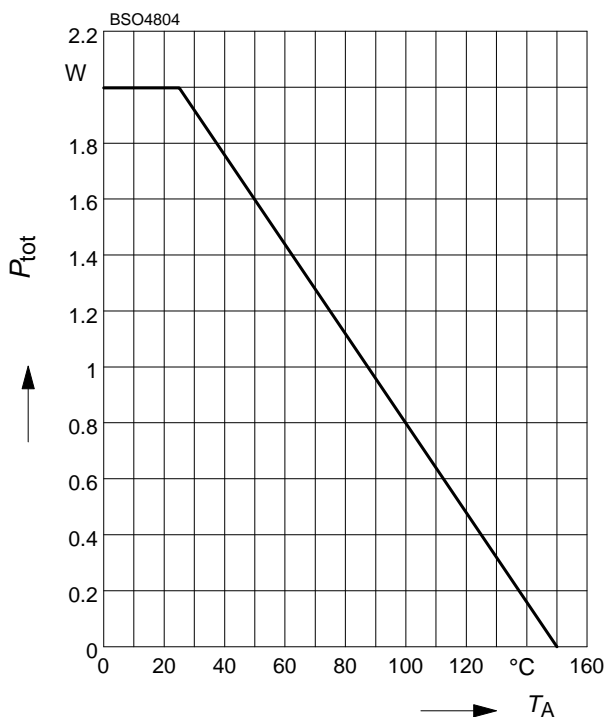
| | | | | | | |
|-----------------------|-----------------|---|---|------|-----|----|
| Gate to source charge | Q_{gs} | $V_{DD} = 15\text{V}$, $I_D = 8\text{A}$ | - | 1.9 | 2.4 | nC |
| Gate to drain charge | Q_{gd} | | - | 5.8 | 8.7 | |
| Gate charge total | Q_g | $V_{DD} = 15\text{V}$, $I_D = 8\text{A}$, $V_{GS} = 0\text{ to }5\text{V}$ | - | 13.5 | 17 | |
| Output charge | Q_{oss} | $V_{DS} = 15\text{V}$, $I_D = 8\text{A}$, $V_{GS} = 0\text{V}$ | - | 10.3 | 13 | |
| Gate plateau voltage | $V_{(plateau)}$ | $V_{DD} = 15\text{V}$, $I_D = 8\text{A}$ | - | 2.8 | - | V |

Reverse Diode

| | | | | | | |
|--|----------|---|---|-----|-----|----|
| Inverse diode continuous forward current | I_S | $T_A = 25^{\circ}\text{C}$ | - | - | 1.8 | A |
| Inverse diode direct current, pulsed | I_{SM} | | - | - | 32 | |
| Inverse diode forward voltage | V_{SD} | $V_{GS} = 0\text{V}$, $I_F = 1.8\text{A}$ | - | 0.9 | 1.3 | V |
| Reverse recovery time | t_{rr} | $V_R = 15\text{V}$, $I_F = I_S$, $di_F/dt = 100\text{A}/\mu\text{s}$ | - | 24 | 30 | ns |
| Reverse recovery charge | Q_{rr} | | - | 16 | 20 | nC |

1 Power dissipation

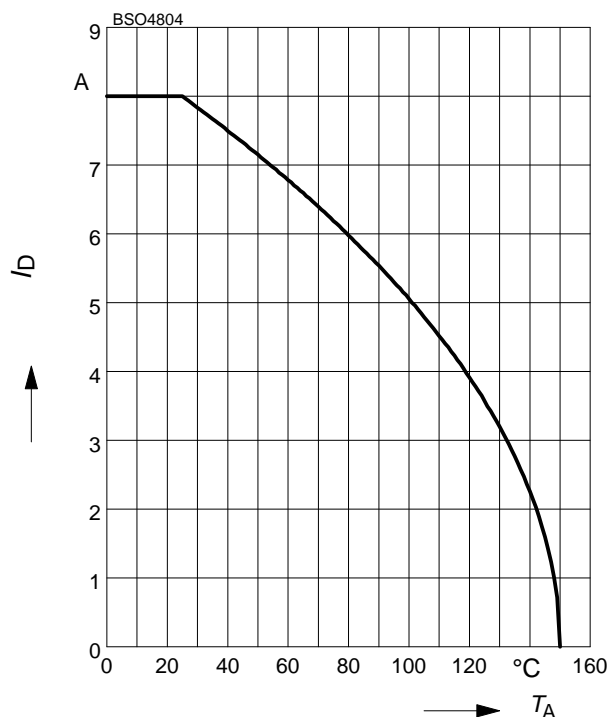
$$P_{\text{tot}} = f(T_A)$$



2 Drain current

$$I_D = f(T_A)$$

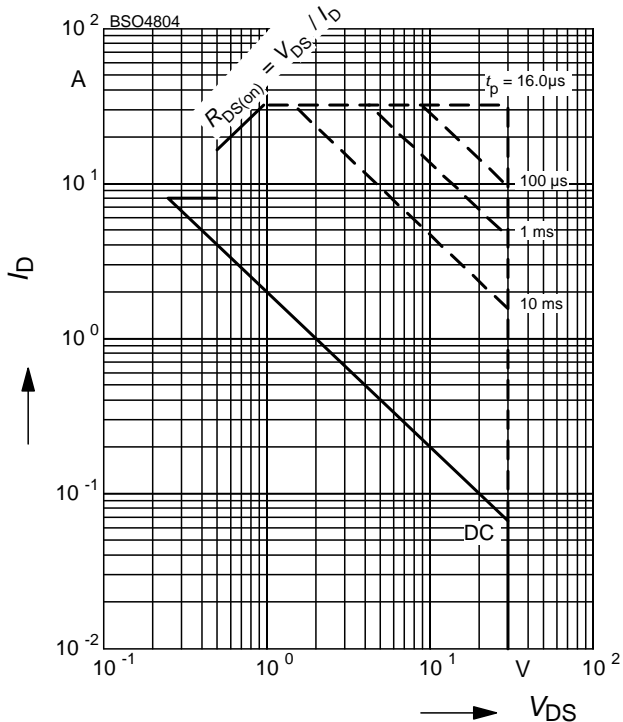
parameter: $V_{GS} \geq 10$ V



3 Safe operating area

$$I_D = f(V_{DS})$$

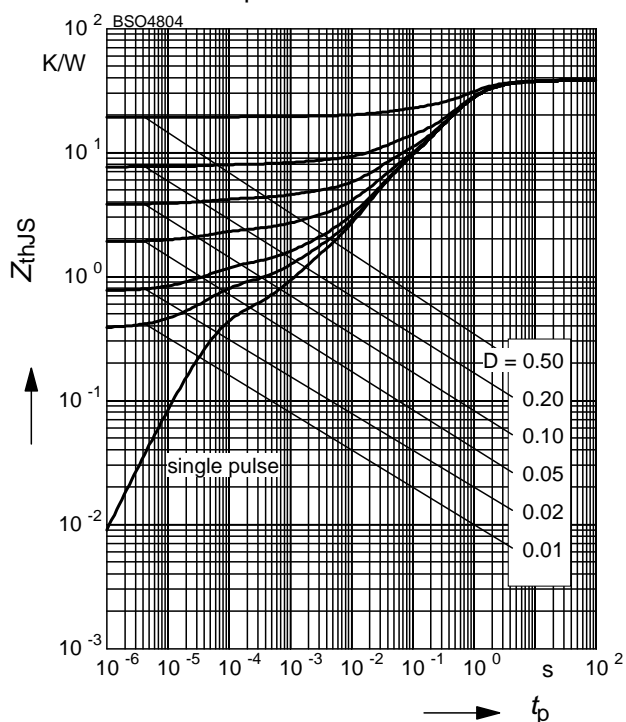
parameter: $D = 0$, $T_A = 25$ °C



4 Transient thermal impedance

$$Z_{\text{thJS}} = f(t_p)$$

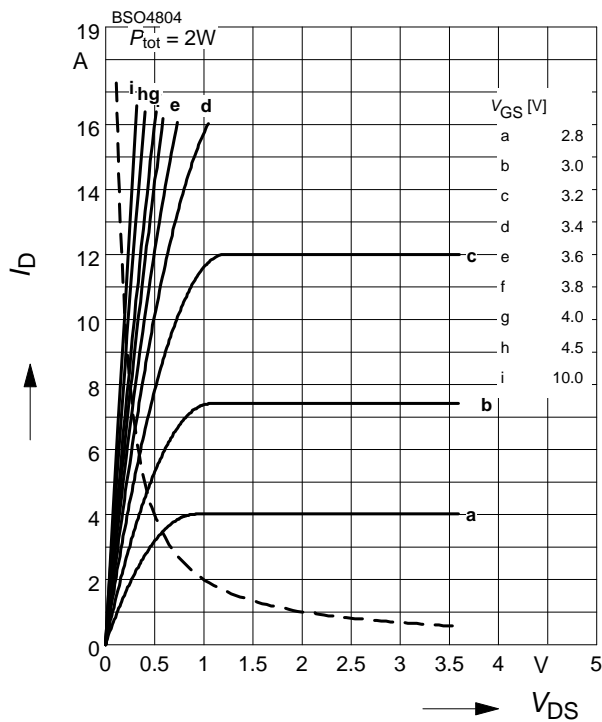
parameter: $D = t_p/T$



5 Typ. output characteristic

$$I_D = f(V_{DS}); T_j = 25^\circ\text{C}$$

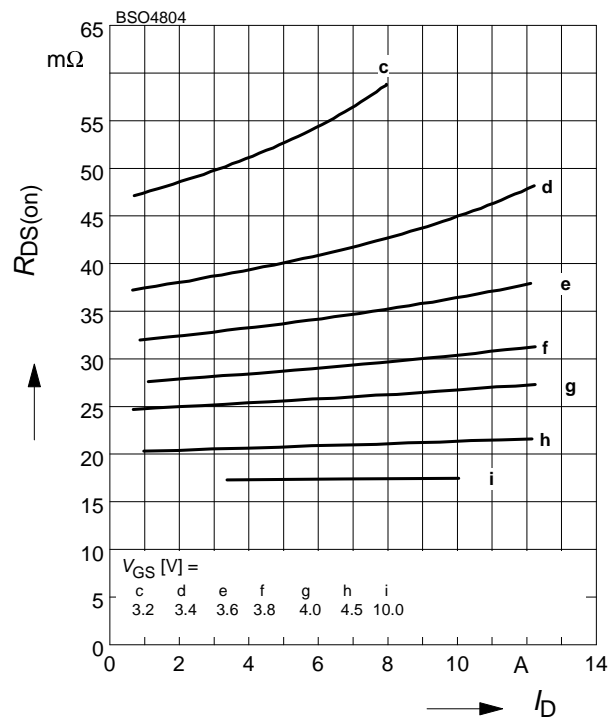
parameter: $t_p = 80 \mu\text{s}$



6 Typ. drain-source on resistance

$$R_{DS(on)} = f(I_D)$$

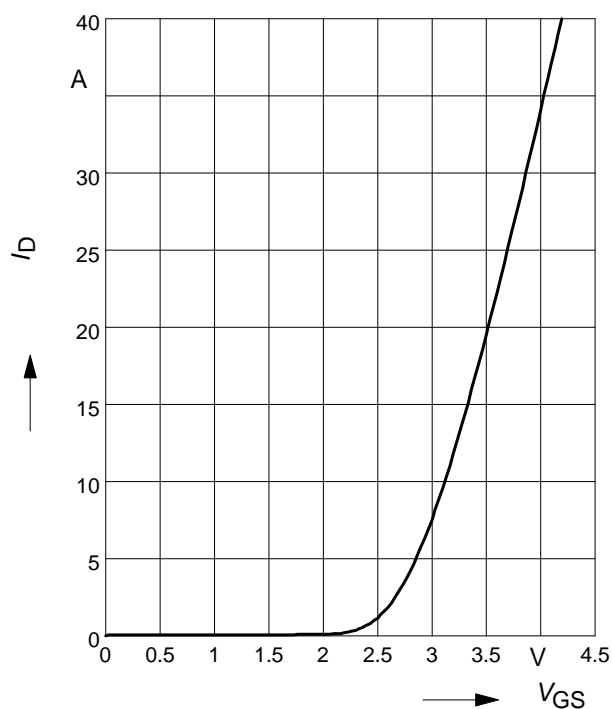
parameter: V_{GS}



7 Typ. transfer characteristics

$$I_D = f(V_{GS}); V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$$

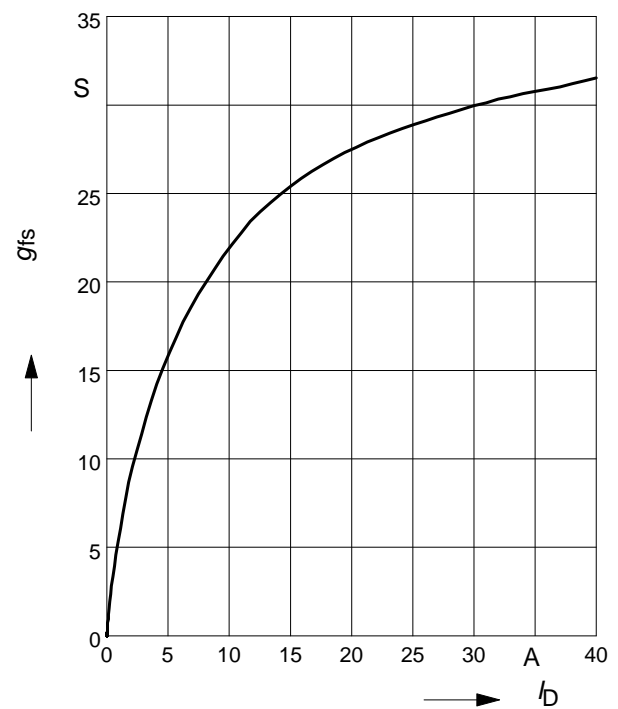
parameter: $t_p = 80 \mu\text{s}$



8 Typ. forward transconductance

$$g_{fs} = f(I_D); T_j = 25^\circ\text{C}$$

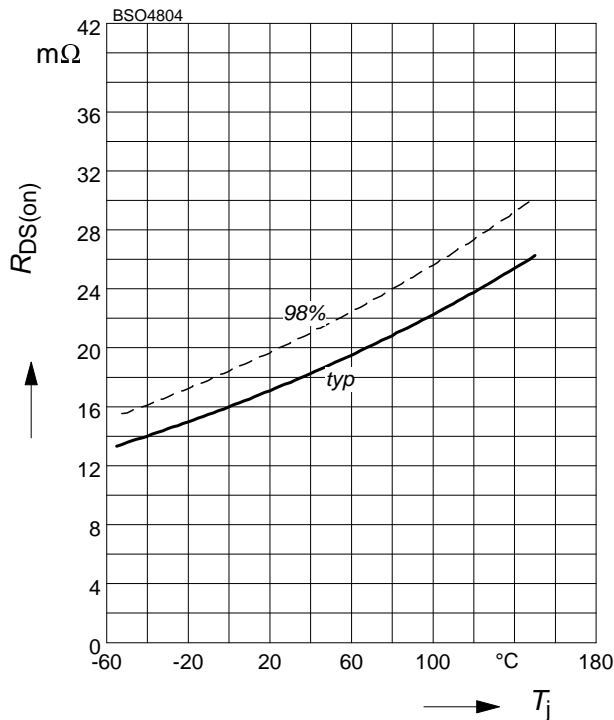
parameter: g_{fs}



9 Drain-source on-state resistance

$$R_{DS(on)} = f(T_j)$$

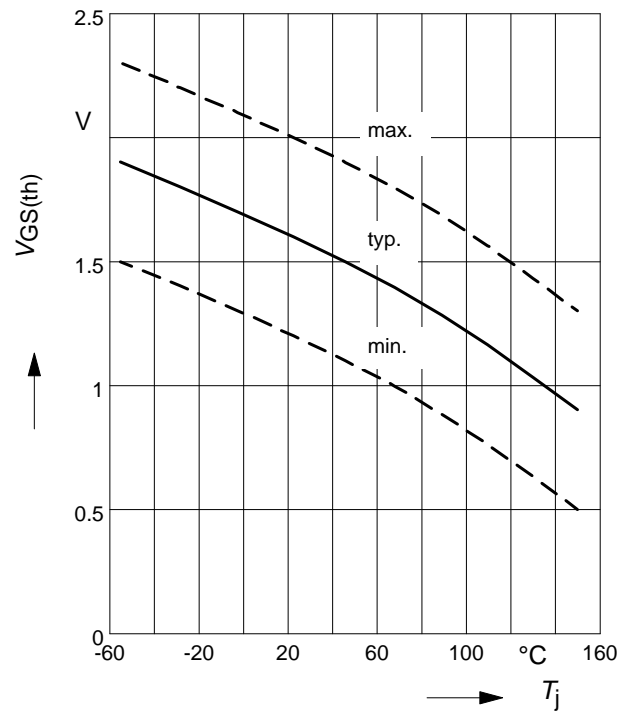
parameter: $I_D = 8\text{ A}$, $V_{GS} = 10\text{ V}$



10 Gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

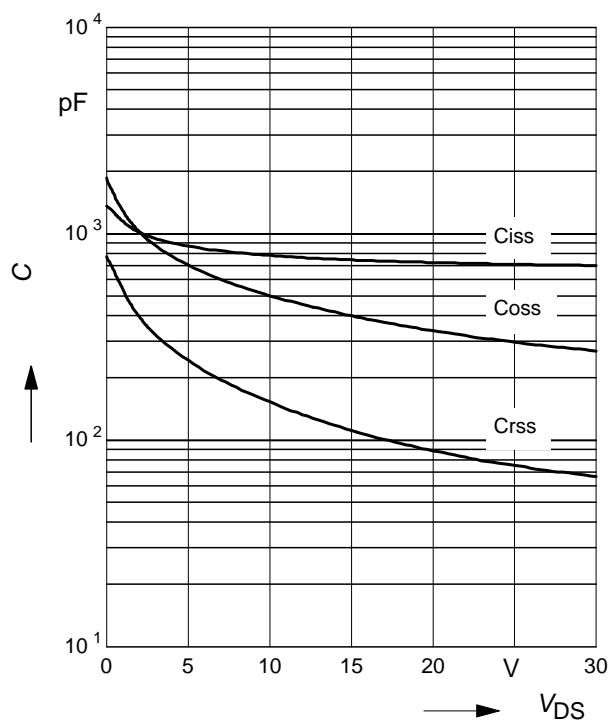
parameter: $V_{GS} = V_{DS}$, $I_D = 30\text{ μA}$



11 Typ. capacitances

$$C = f(V_{DS})$$

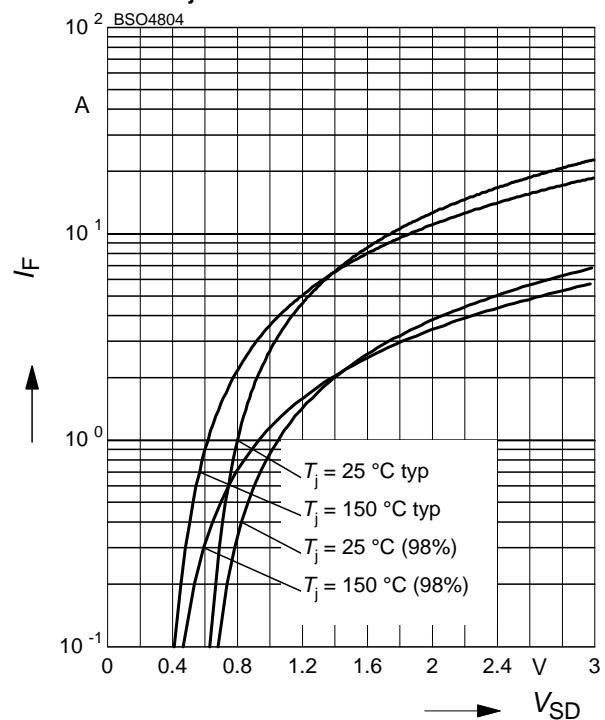
parameter: $V_{GS} = 0\text{ V}$, $f = 1\text{ MHz}$



12 Forward character. of reverse diode

$$I_F = f(V_{SD})$$

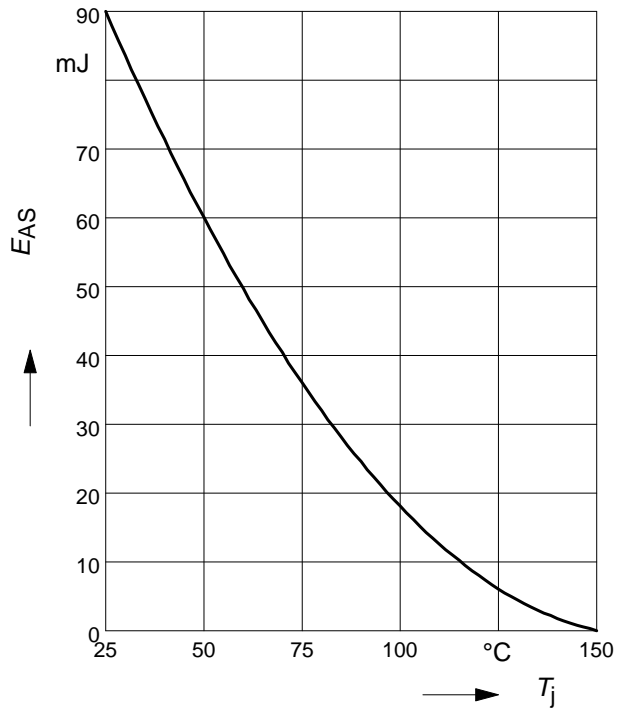
parameter: T_j , $t_p = 80\text{ μs}$



13 Typ. avalanche energy

$$E_{AS} = f(T_j)$$

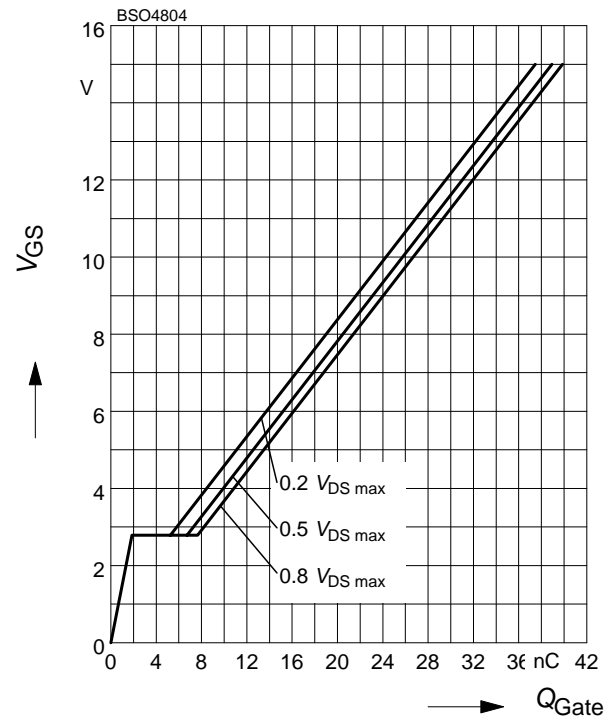
par.: $I_D = 8\text{ A}$, $V_{DD} = 25\text{ V}$, $R_{GS} = 25\ \Omega$



14 Typ. gate charge

$$V_{GS} = f(Q_{Gate})$$

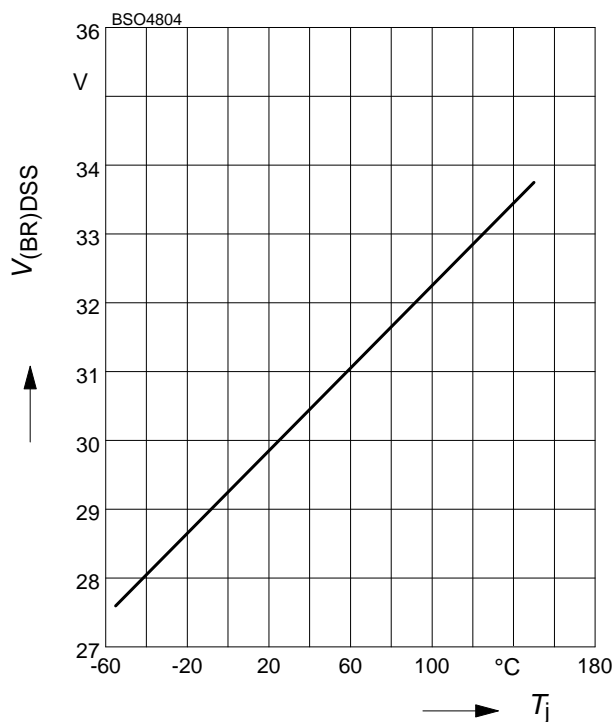
parameter: $I_D = 8\text{ A}$ pulsed



15 Drain-source breakdown voltage

$$V_{(BR)DSS} = f(T_j)$$

parameter: $I_D = 10\text{ mA}$



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